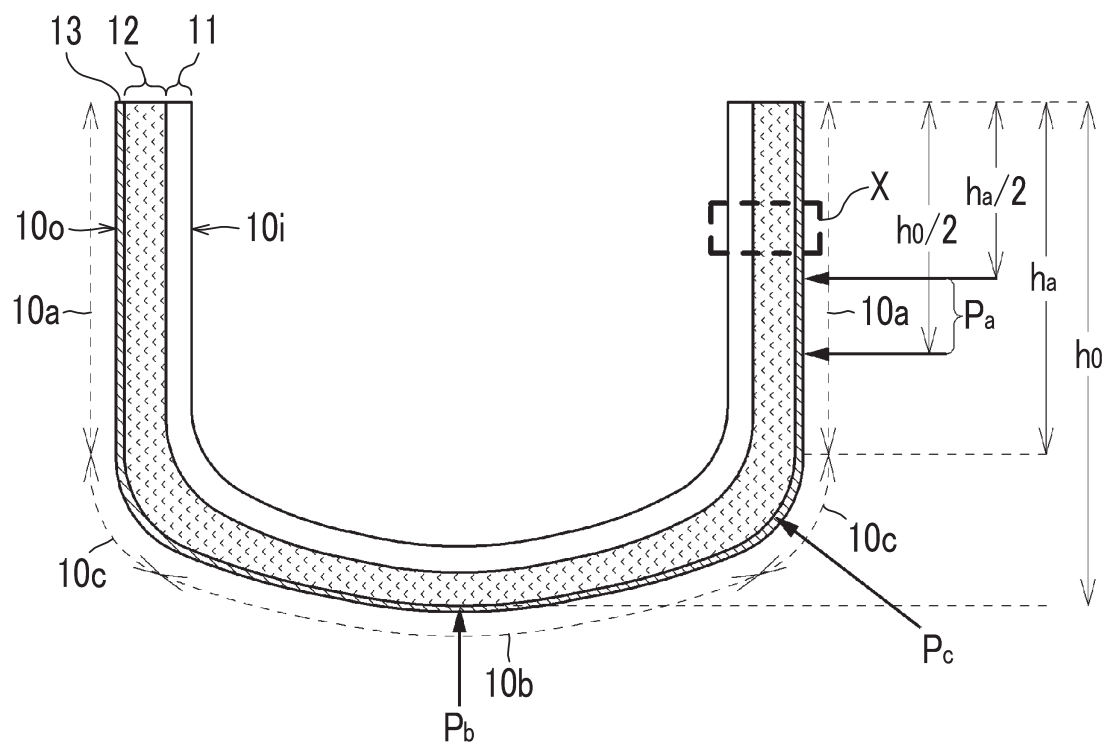
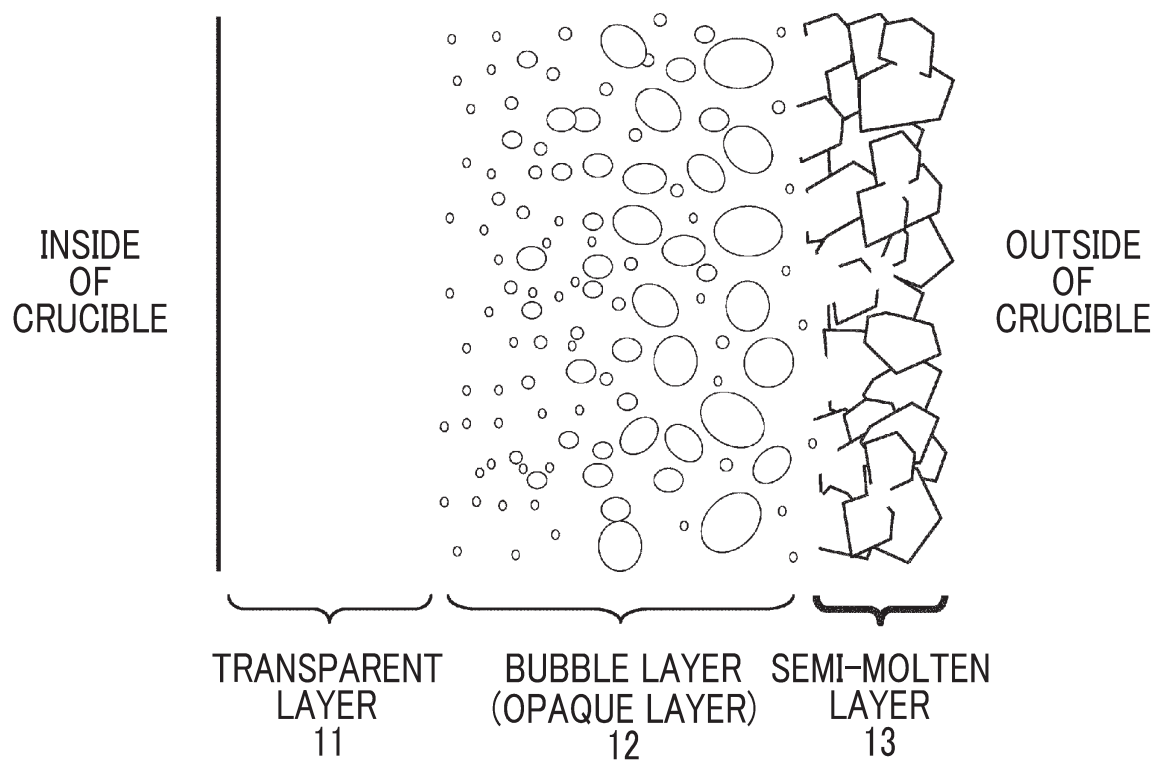


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FIG. 1

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FIG. 2



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FIG. 3

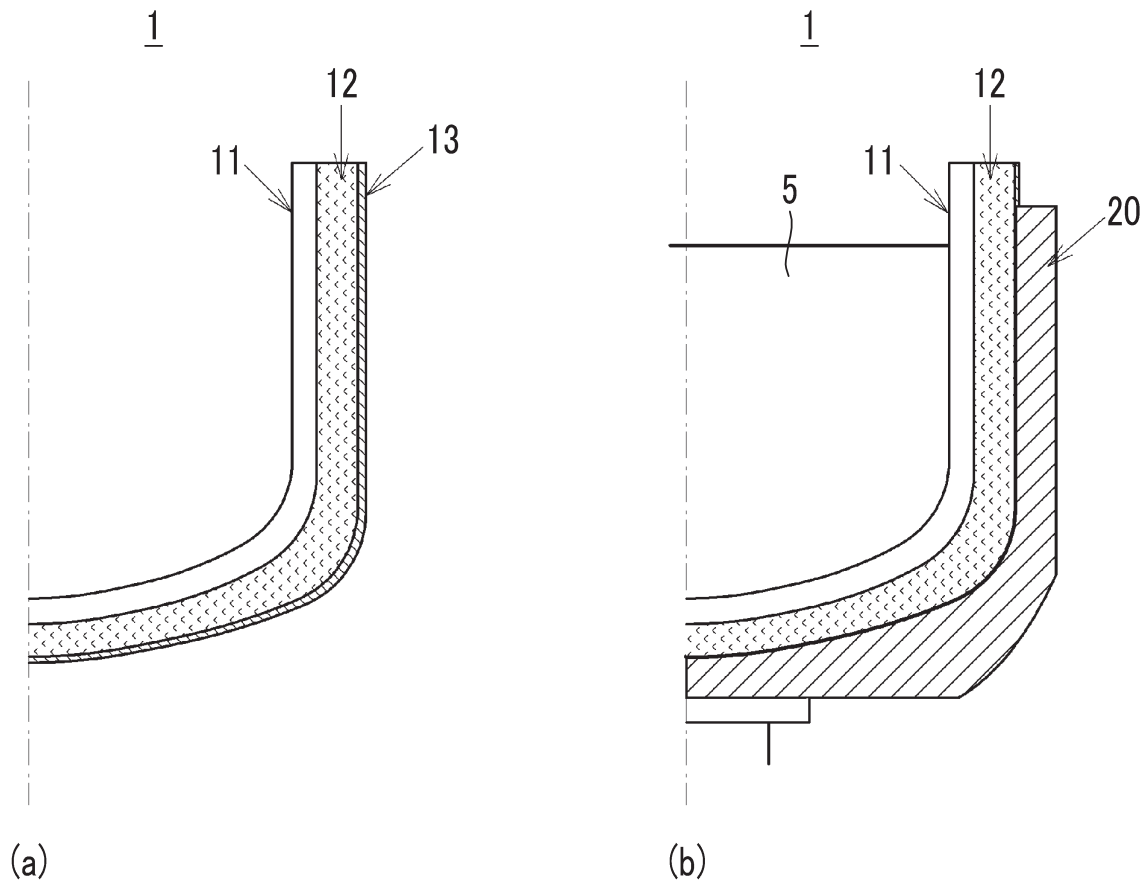
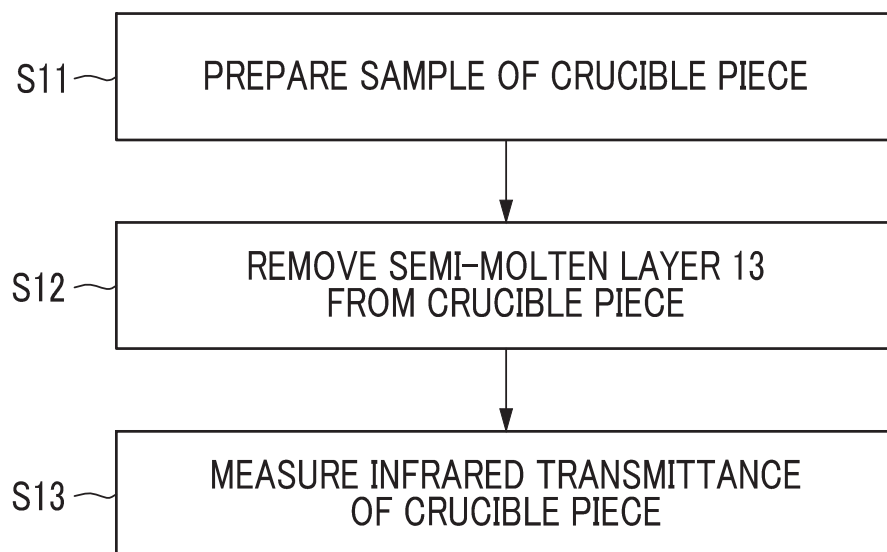
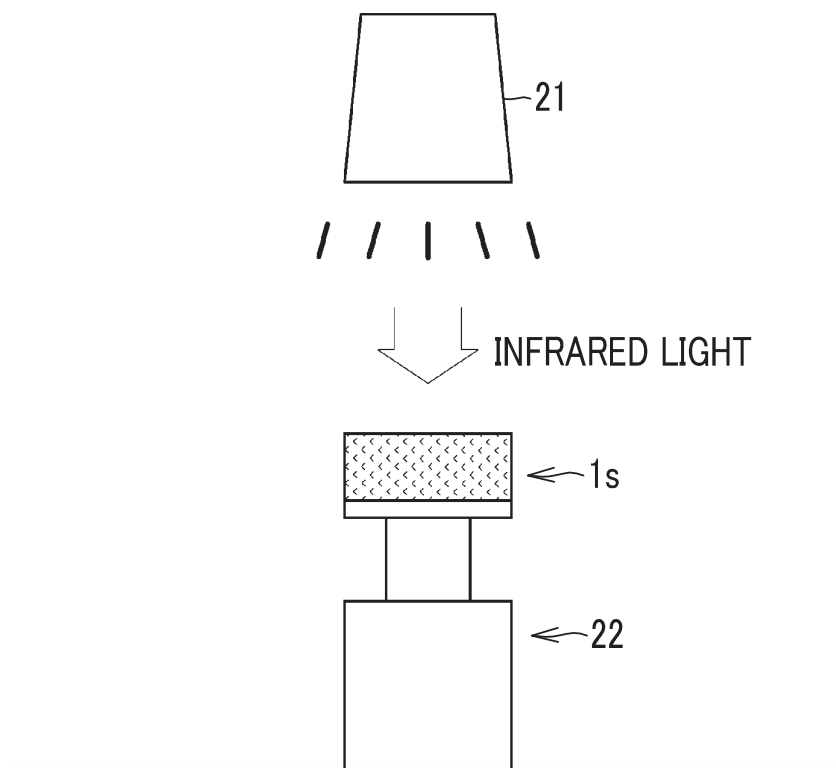


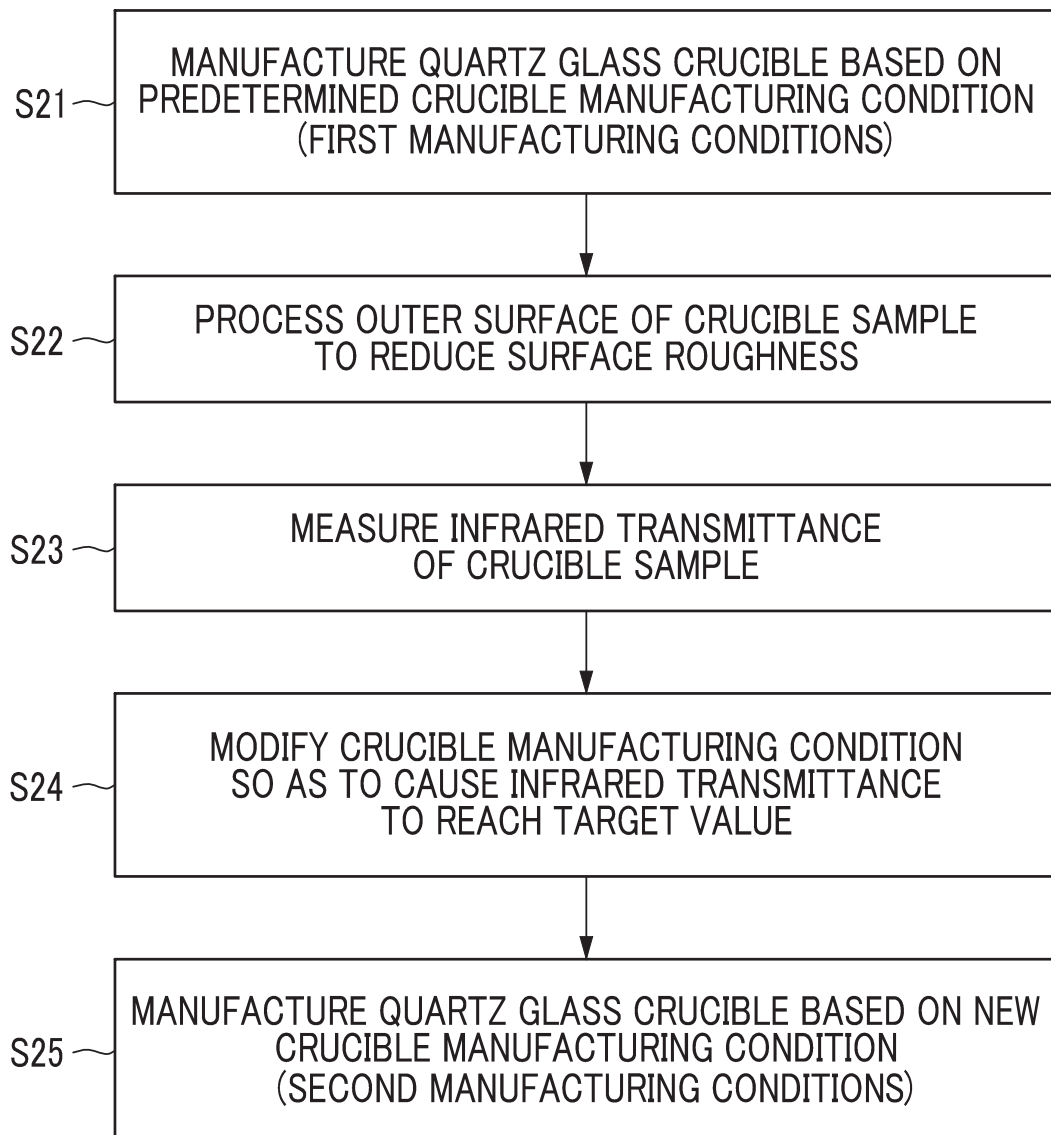
FIG. 4



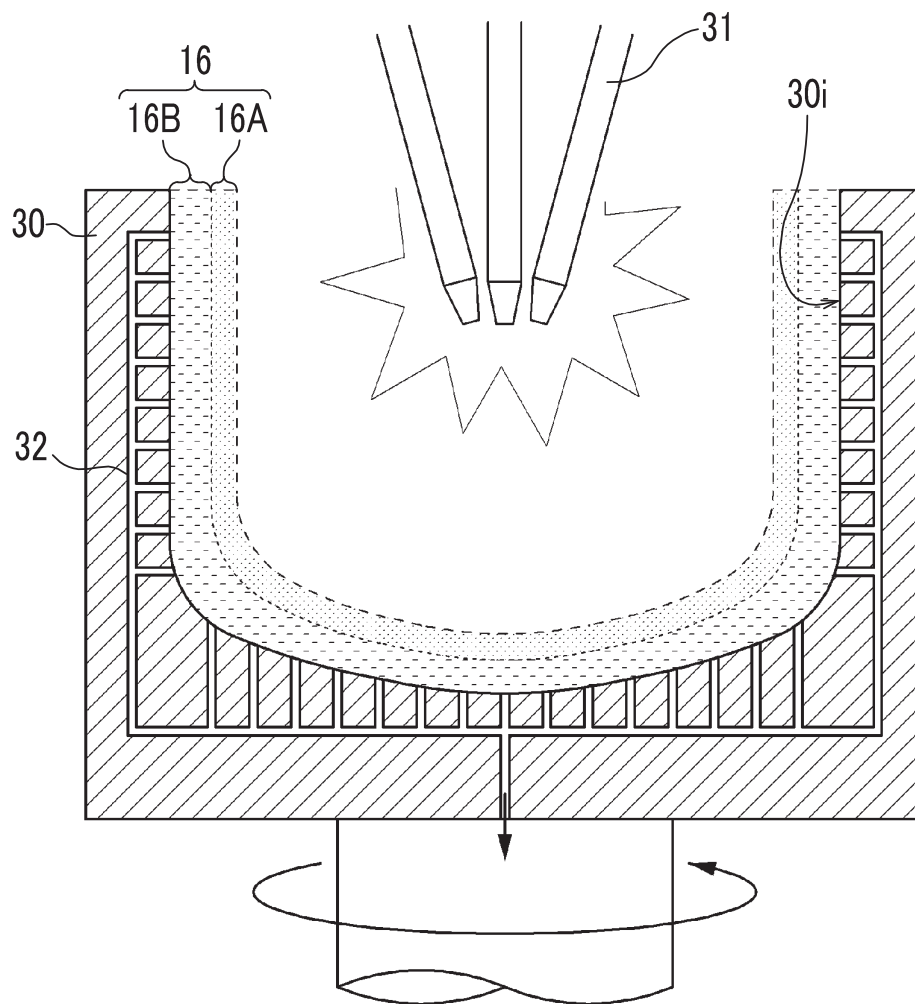
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FIG. 5



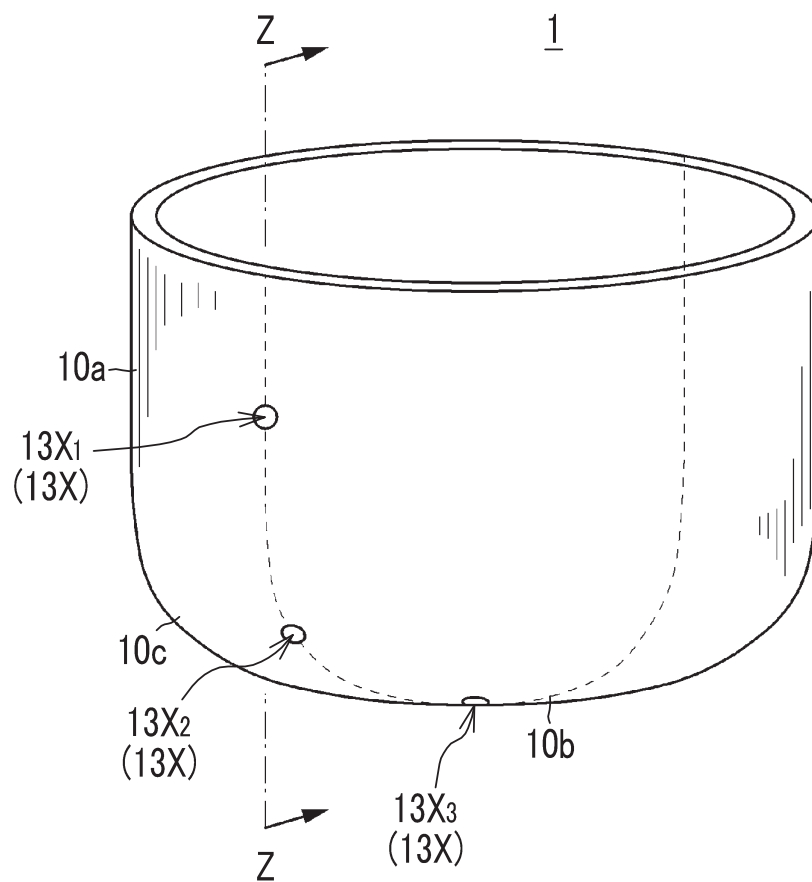
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FIG. 6



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FIG. 7



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FIG. 8



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FIG. 9

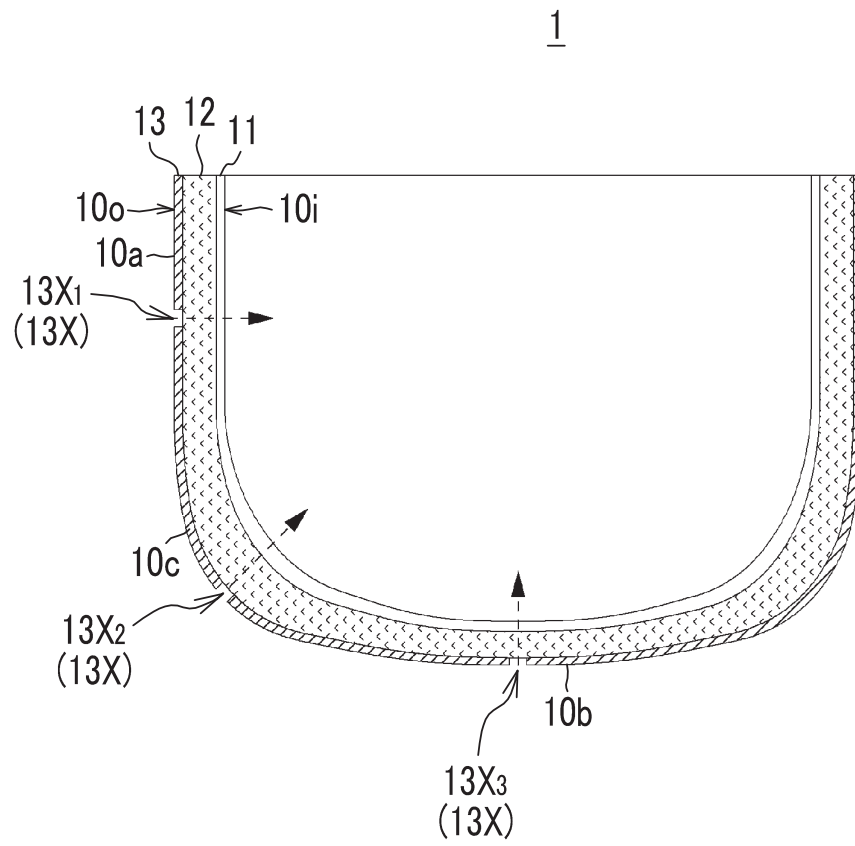


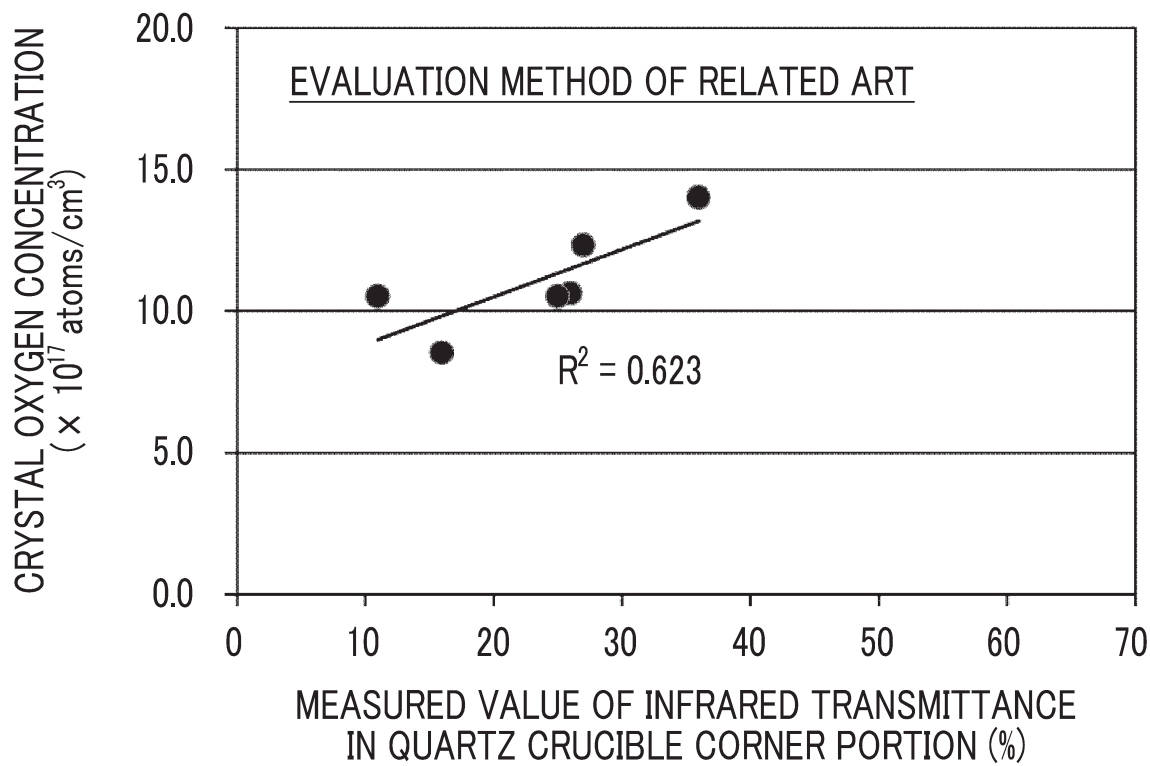
FIG. 10

CRUCIBLE SAMPLE	INFRARED TRANSMITTANCE (%) OF CRUCIBLE MEASURED BY REMOVING SEMI-MOLTEN LAYER			REDUCTION IN OXYGEN CONCENTRATION ($\leq 12 \times 10^{17}$ atoms/cm ³)	OCCURRENCE OF DISLOCATION	OVERALL DETERMINATION
	SIDE WALL PORTION	CORNER PORTION	BOTTOM PORTION			
#1 (EXAMPLE 1)	55	46	52	SUFFICIENTLY SATISFIED	ABSENT	O
#2 (EXAMPLE 2)	70	25	50	SUFFICIENTLY SATISFIED	ABSENT	O
#3 (EXAMPLE 3)	56	33	36	SUFFICIENTLY SATISFIED	ABSENT	O
#4 (EXAMPLE 4)	84	46	57	SUFFICIENTLY SATISFIED	ABSENT	O
#5 (EXAMPLE 5)	52	51	70	SATISFIED	ABSENT	O
#6 (EXAMPLE 6)	46	39	51	SATISFIED	ABSENT	O
#7 (COMPARATIVE EXAMPLE 1)	86	65	59	NOT SATISFIED	ABSENT	x
#8 (COMPARATIVE EXAMPLE 2)	52	58	72	NOT SATISFIED	ABSENT	x
#9 (COMPARATIVE EXAMPLE 3)	56	20	33	SUFFICIENTLY SATISFIED	PRESENT	x
#10 (COMPARATIVE EXAMPLE 4)	39	24	46	SUFFICIENTLY SATISFIED	PRESENT	x
#11 (COMPARATIVE EXAMPLE 5)	50	20	40	SUFFICIENTLY SATISFIED	PRESENT	x
#12 (COMPARATIVE EXAMPLE 6)	50	55	40	NOT SATISFIED	ABSENT	x

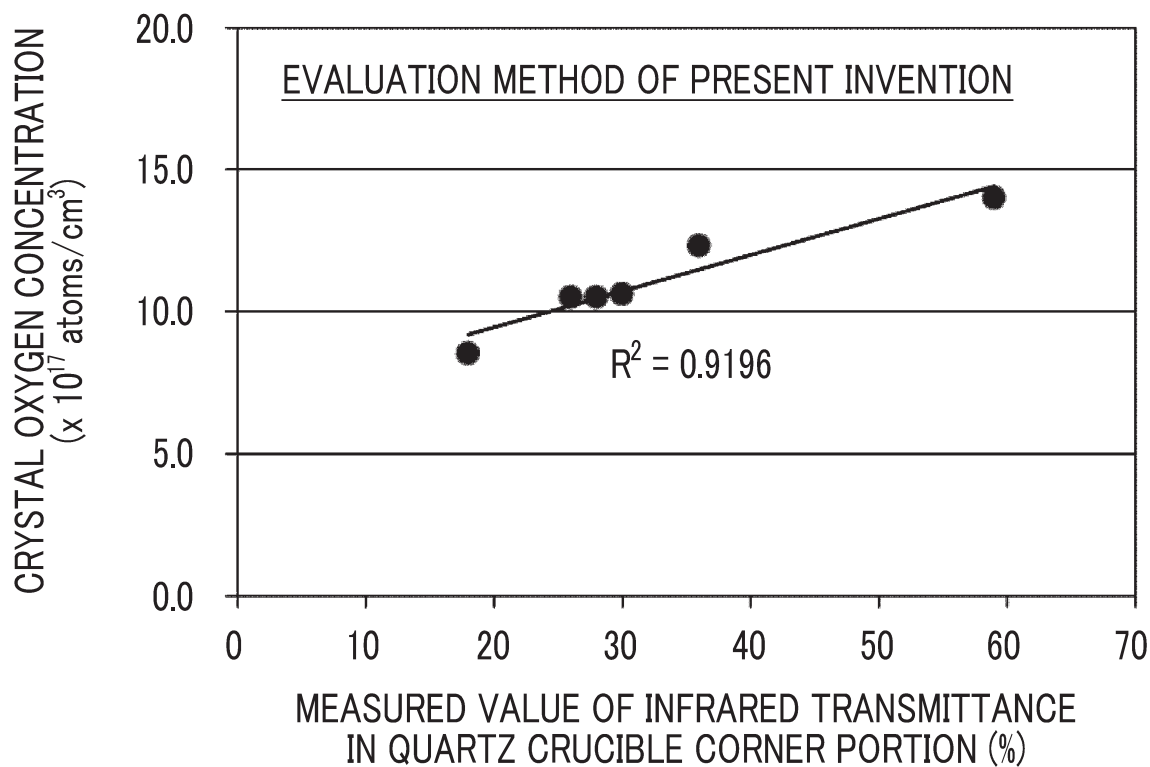
FIG. 11

QUARTZ CRUCIBLE SAMPLE	MEASUREMENT RESULTS (%) OF INFRARED TRANSMITTANCE OF CORNER PORTION		CRYSTAL OXYGEN CONCENTRATION ($\times 10^{17}$ atoms/cm ³)
	BEFORE REMOVING SEMI-MOLTEN LAYER (EVALUATION METHOD OF RELATED ART)	BEFORE REMOVING SEMI-MOLTEN LAYER (EVALUATION METHOD OF PRESENT INVENTION)	
A1, A2	11	26	10.5
B1, B2	26	30	10.6
C1, C2	25	28	10.5
D1, D2	27	36	12.3
E1, E2	16	18	8.5
F1, F2	36	55	14.0

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FIG. 12



(a)



(b)